



# A New Front-end ASIC for GEM detectors with Time and Charge Measurement Capabilities



FRONTIER DETECTORS FOR FRONTIER PHYSICS  
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F. Ciciriello<sup>1</sup>, F. Corsi<sup>1</sup>, G. De Robertis<sup>2</sup>, G. Felici<sup>3</sup>, F. Loddo<sup>2</sup>,  
C. Marzocca<sup>1</sup>, G. Matarrese<sup>1</sup>, A. Ranieri<sup>2</sup>

<sup>1</sup>DEI – Politecnico di Bari and INFN – Sezione di Bari, Italy

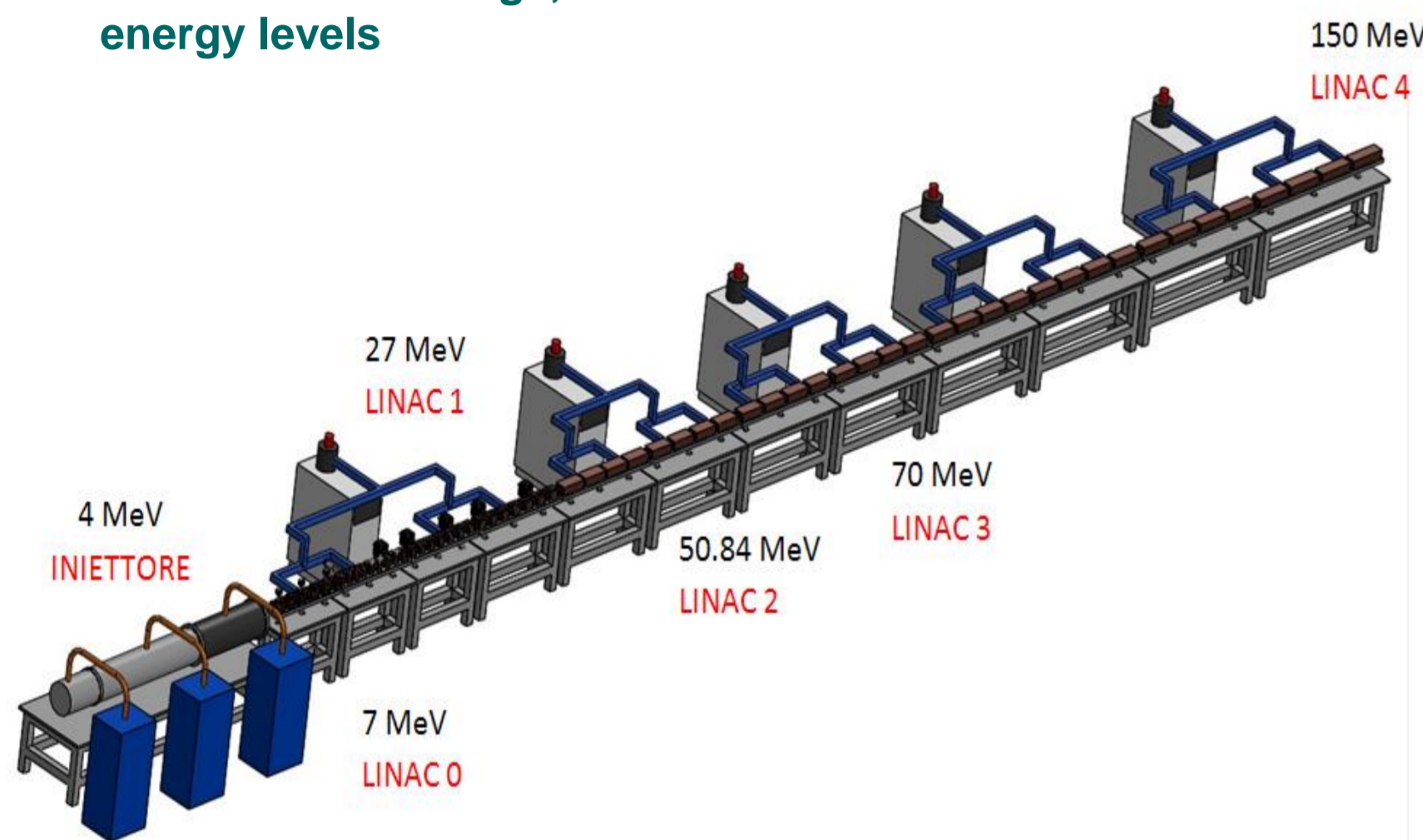
<sup>2</sup>INFN – Sezione di Bari, Italy

<sup>3</sup>INFN – Frascati National Laboratories, Italy

## Motivations and purposes

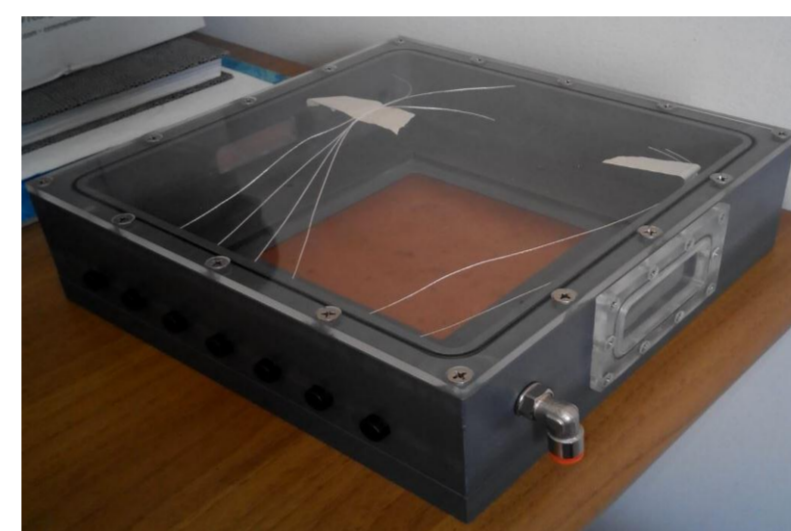
### The AMIDERHA project

- Construction of a new proton-therapy facility in the Apulia region
- Based on multi-stage, cascaded LINAC to obtain different energy levels



### Beam monitoring

- Accurate system of beam monitoring needed
- Based on Gas Electron Multiplier (GEM) detectors
  - Flexibility in size and geometry
  - High rate capability (up to 50MHz/cm<sup>2</sup>)
  - Good spatial resolution (down to 50÷100 μm) and time resolution (down to 4.5 ns)
  - Low mass contribution
  - Large gain with triple GEM structures



Development of the GEM for AMIDERHA: mechanical gas volume

### Front-end ASIC for GEM detectors

- Multichannel ASIC needed for compactness and power consumption
- Charge measurement capability, to improve the spatial resolution (charge centroid technique)
- Accurate trigger signal, to allow for coincidence analysis among different GEM layers

#### ASIC main features

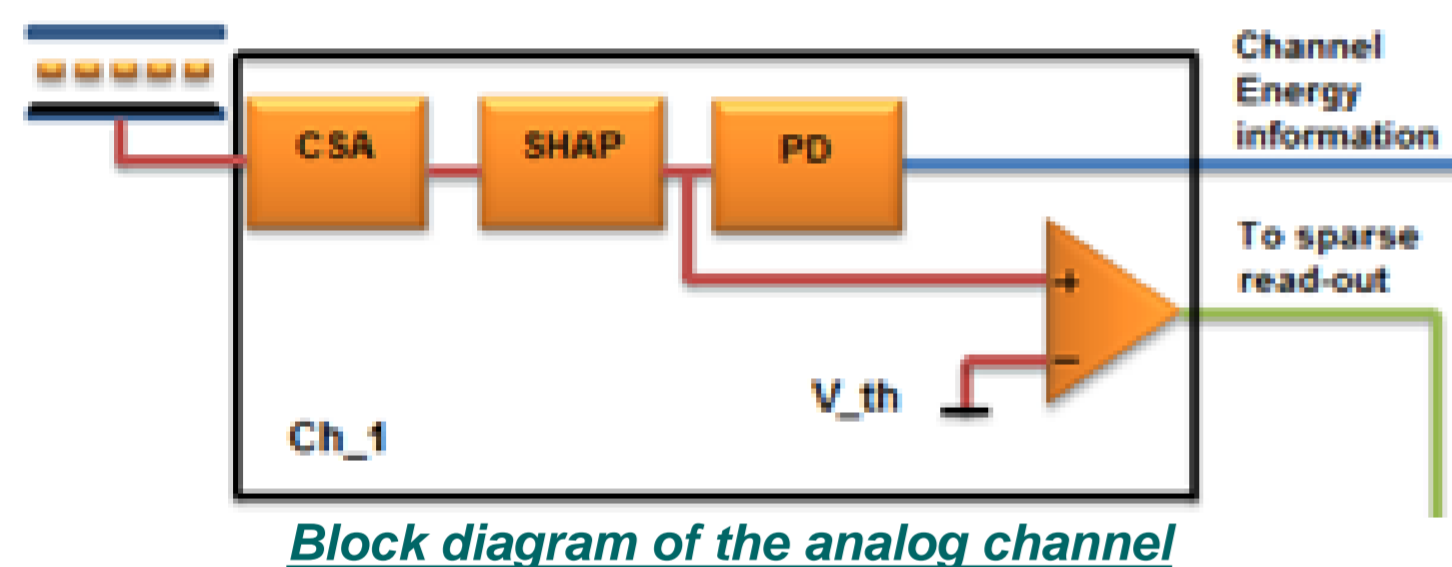
- Technology CMOS AMS 0.35μm
- 32 channels
- Power supply voltage 3.3V
- Integrated 8 bit ADC
- Fast LVDS link for data transfer

Sensitivity	15mV/fC
Dynamic range	80fC
Non-linearity error	< 1%
Equivalent input noise charge (ENC)	< 650e-
Detector capacitance	≅10pF

Main specifications for the GEM front-end

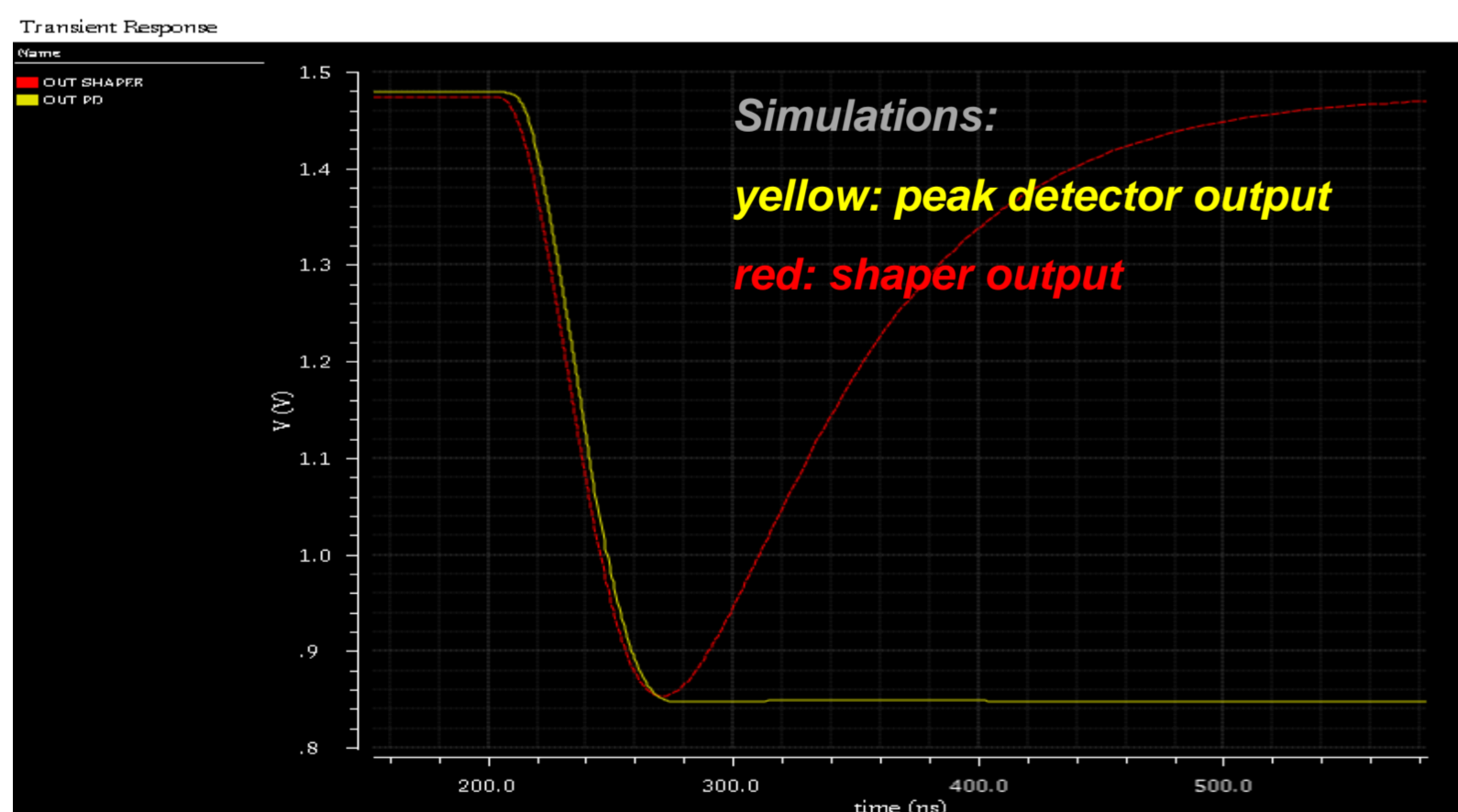
## Main building blocks of the ASIC

### Analog channel



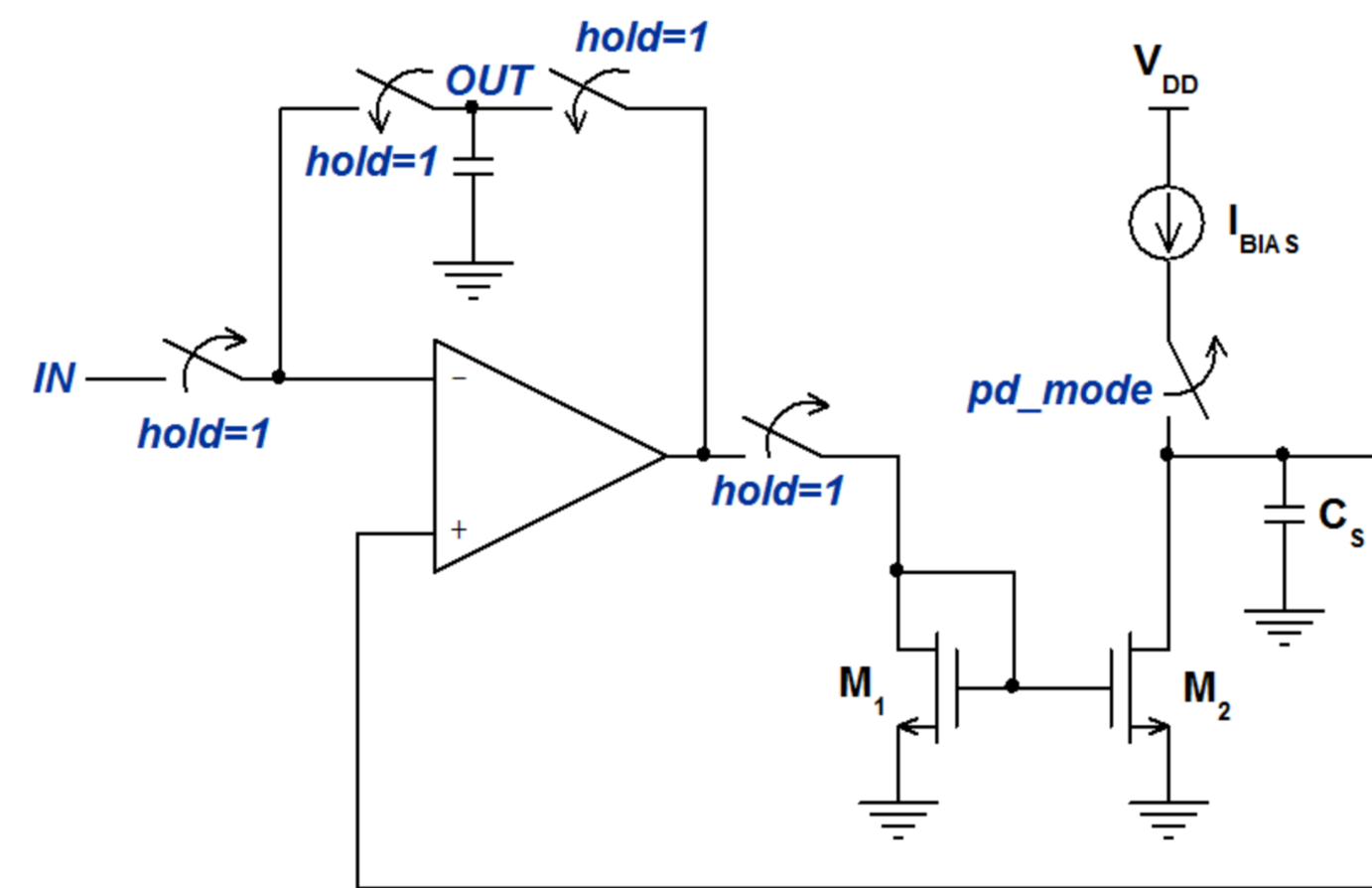
Block diagram of the analog channel

- Classic CSA+shaper front-end structure
- CSA: straight cascode with active reset of the integration capacitance  $C_F=180fF$  (PMOS with adjustable bias current)
- Second order shaper with adjustable output baseline, peaking time  $\cong 80ns$
- Peak detector, working as an analog memory, to store the charge information during the read-out
- Leading edge comparator with adjustable threshold



Simulations:  
yellow: peak detector output  
red: shaper output

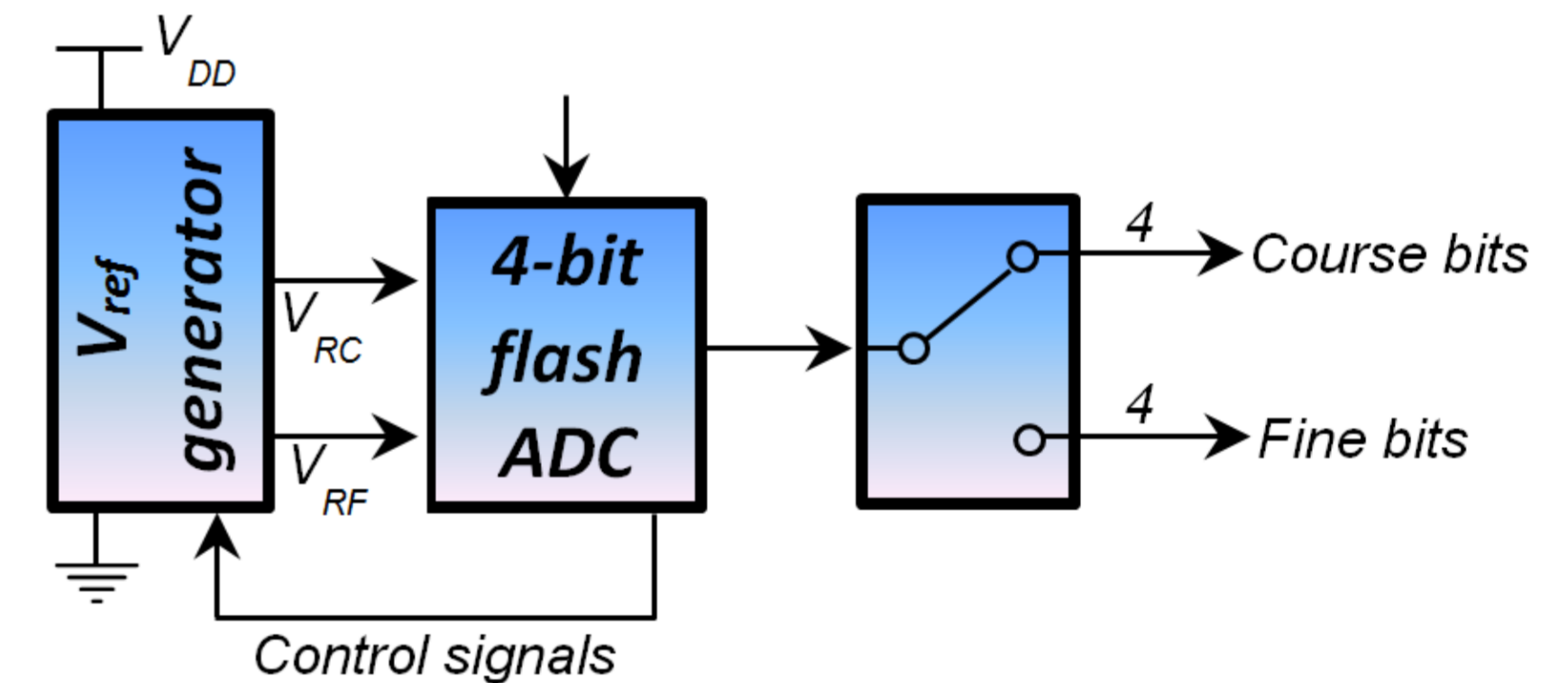
### Peak detector



Three operating modes:

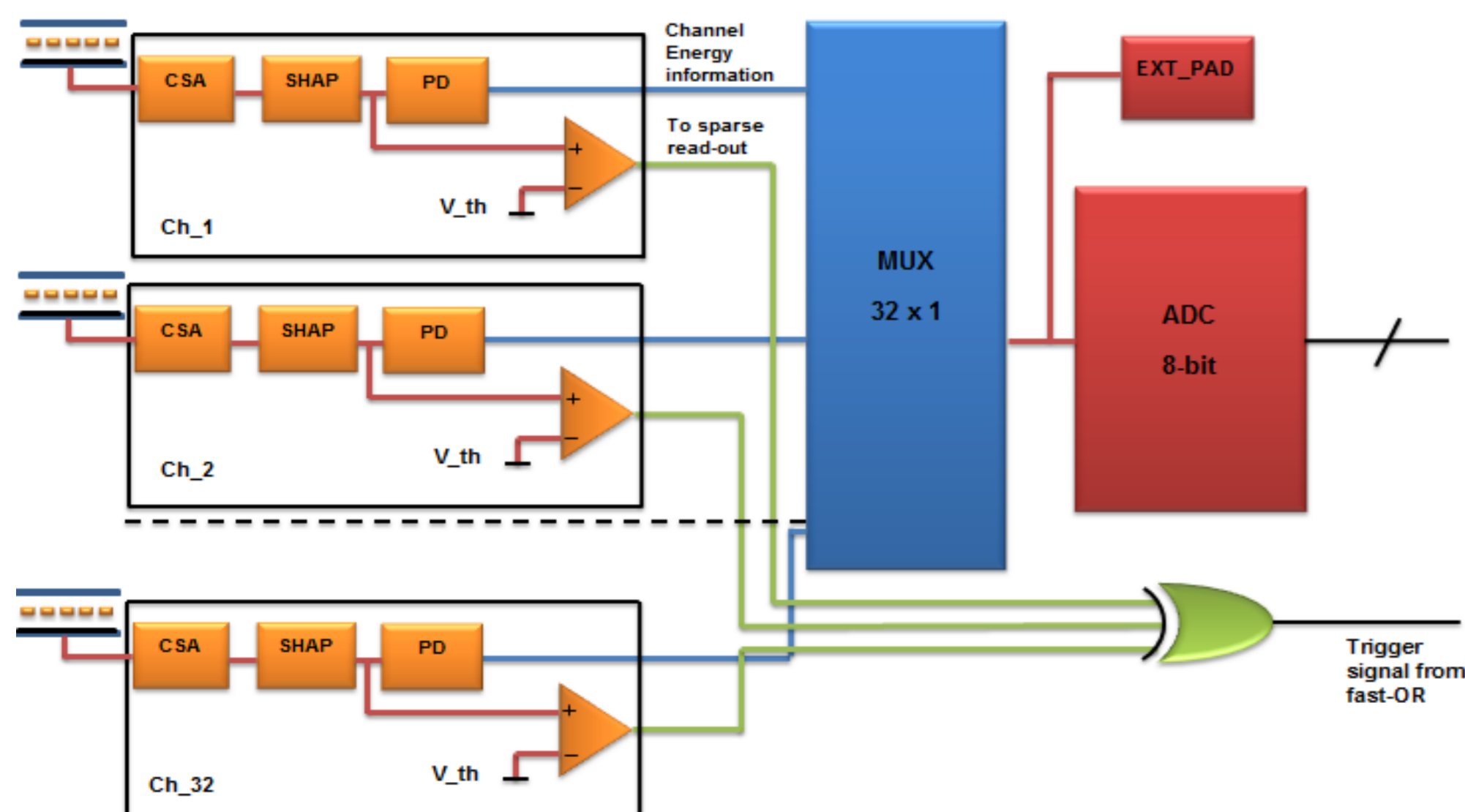
- $pd\_mode=0, hold=0$ : voltage follower mode  
The voltage on  $C_s$  follows the input
- $pd\_mode=1, hold=0$ : peak detection mode  
The voltage on  $C_s$  tracks the peak of the input
- $pd\_mode=1, hold=1$ : analog memory  
The voltage on  $C_s$  is buffered on the output node

### Two-step flash, subranging 8-bit ADC

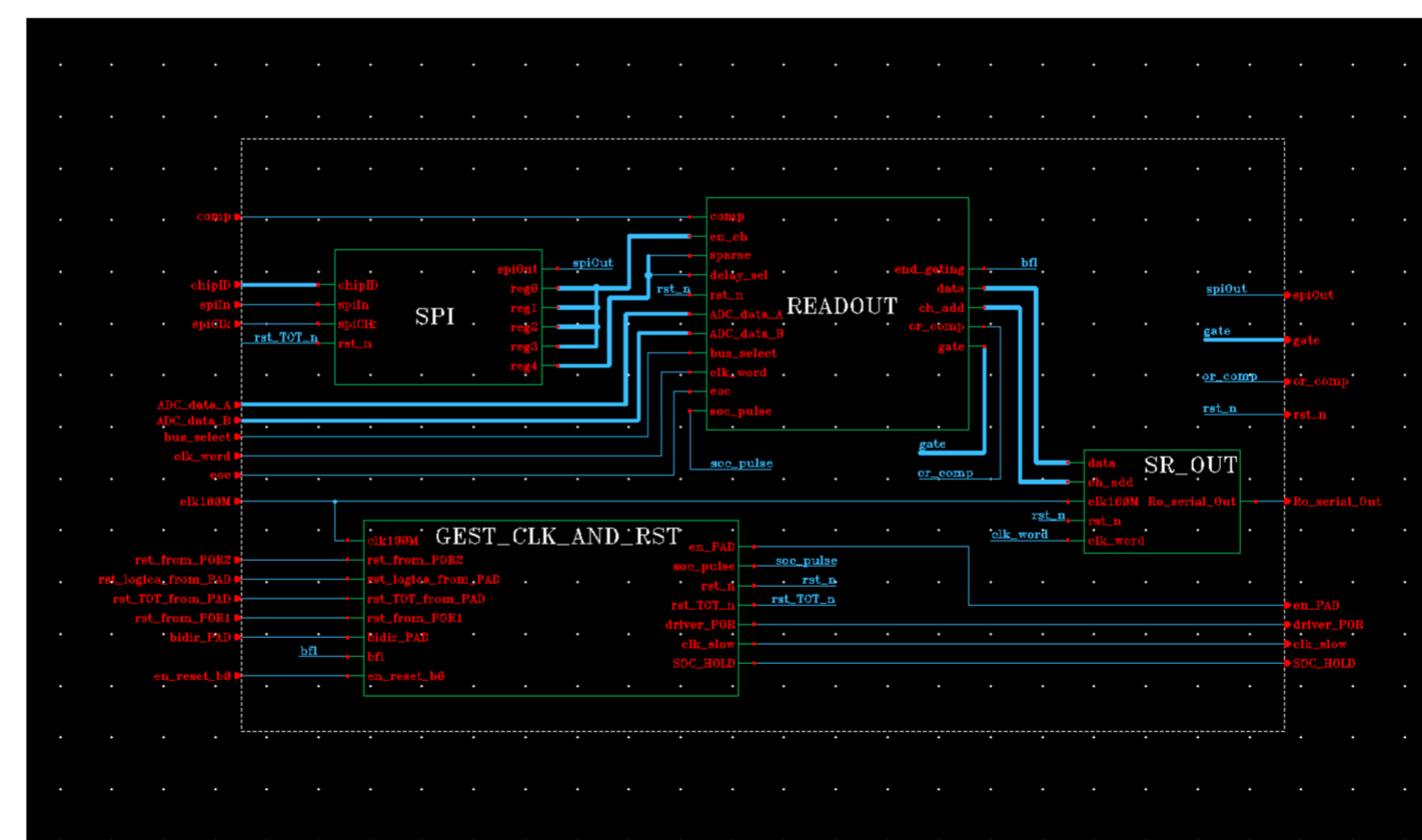


- Two-phase conversion: coarse and fine, exploiting the same comparators and different references  $V_{RC}$  and  $V_{RF}$
- Resistor ladder for reference generation
- Two ADC modules working in interleaving: one conversion per clock cycle, maximum conversion rate 20MS/s
- Correction logic for "bubble" errors
- Total power consumption 24mW

## Architecture of the ASIC



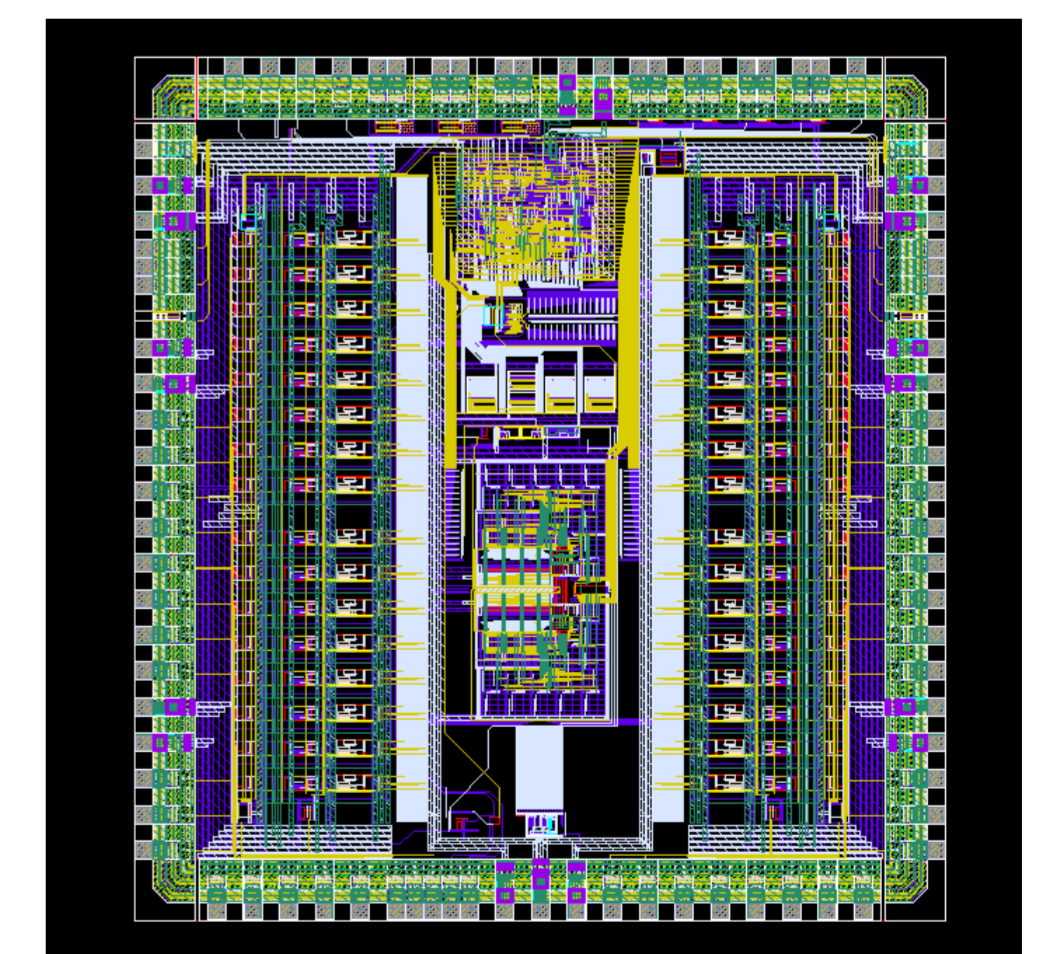
### Digital part



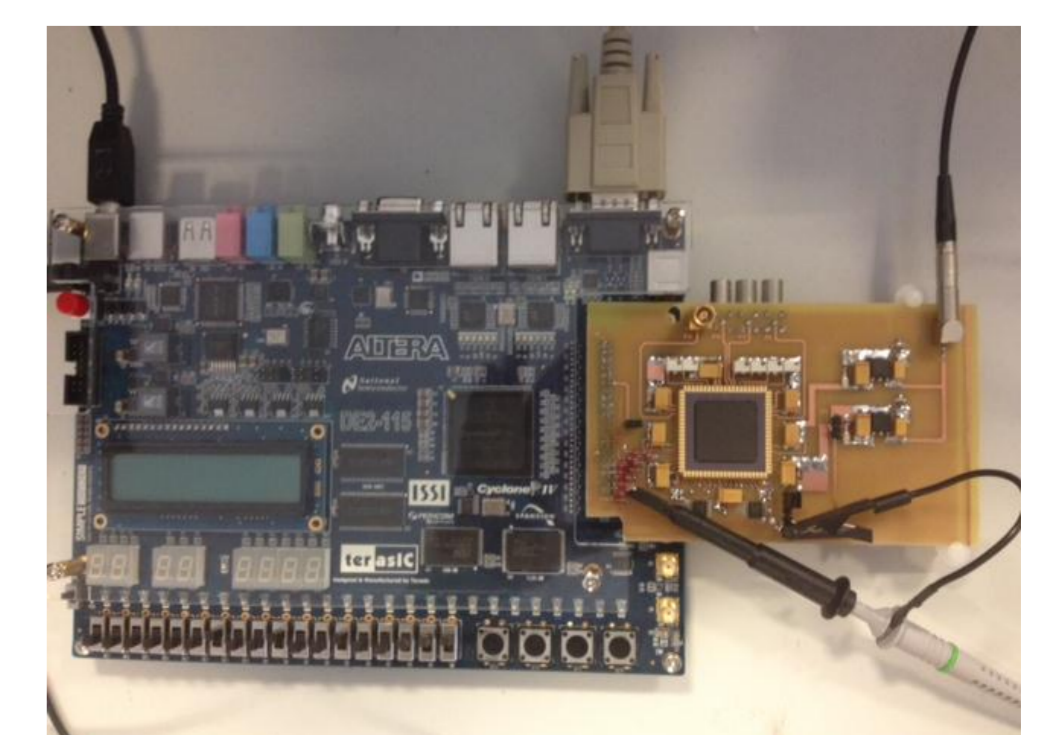
- READOUT: management of the sparse and serial read-out modes
- SPI: configuration interface (two 8-bit DACs, three 10-bit DACs, channel masking, setting of the read-out mode, test mode)
- SR\_OUT: data serializer for the 100Mbit/s LVDS output link
- GEST\_CLK\_AND\_RST: clock and reset management

- PD outputs multiplexed to the ADC input
- Trigger formation: fast-OR of the comparator outputs
- Channel maskable through configuration flags
- Internal bias generator based on bandgap reference

### Layout



- 4.6 x 4.9 mm<sup>2</sup>, package JLCC 84 pins



- ASIC assembled on the test board